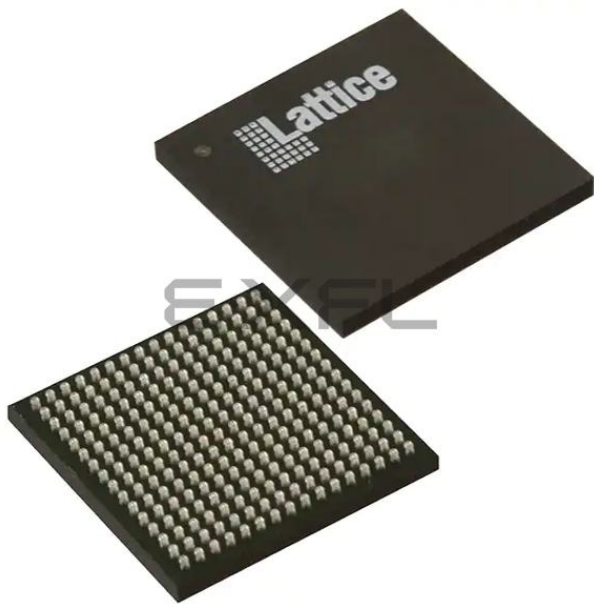




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Details

Product Status	Active
Number of LABs/CLBs	11000
Number of Logic Elements/Cells	44000
Total RAM Bits	1990656
Number of I/O	197
Number of Gates	-
Voltage - Supply	1.045V ~ 1.155V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	256-LFBGA
Supplier Device Package	256-CABGA (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/lattice-semiconductor/lfe5u-45f-6bg256c

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2.3. Routing

There are many resources provided in the ECP5/ECP5-5G devices to route signals individually or as busses with related control signals. The routing resources consist of switching circuitry, buffers and metal interconnect (routing) segments. The ECP5/ECP5-5G family has an enhanced routing architecture that produces a compact design. The Diamond design software tool suites take the output of the synthesis tool and places and routes the design.

2.4. Clocking Structure

ECP5/ECP5-5G clocking structure consists of clock synthesis blocks (sysCLOCK PLL); balanced clock tree networks (PCLK and ECLK trees); and efficient clock logic modules (CLOCK DIVIDER and Dynamic Clock Select (DCS), Dynamic Clock Control (DCC) and DLL). All of these functions are described below.

2.4.1. sysCLOCK PLL

The sysCLOCK PLLs provide the ability to synthesize clock frequencies. The devices in the ECP5/ECP5-5G family support two to four full-featured General Purpose PLLs. The sysCLOCK PLLs provide the ability to synthesize clock frequencies. The architecture of the PLL is shown in Figure 2.5. A description of the PLL functionality follows.

CLKI is the reference frequency input to the PLL and its source can come from two different external CLK inputs or from internal routing. A non-glitchless 2-to-1 input multiplexor is provided to dynamically select between two different external reference clock sources. The CLKI input feeds into the input Clock Divider block.

CLKFB is the feedback signal to the PLL which can come from internal feedback path, routing or an external I/O pin. The feedback divider is used to multiply the reference frequency and thus synthesize a higher frequency clock output.

The PLL has four clock outputs CLKOP, CLKOS, CLKOS2 and CLKOS3. Each output has its own output divider, thus allowing the PLL to generate different frequencies for each output. The output dividers can have a value from 1 to 128. The CLKOP, CLKOS, CLKOS2, and CLKOS3 outputs can all be used to drive the primary clock network. Only CLKOP and CLKOS outputs can go to the edge clock network.

The setup and hold times of the device can be improved by programming a phase shift into the CLKOS, CLKOS2, and CLKOS3 output clocks which will advance or delay the output clock with reference to the CLKOP output clock. This phase shift can be either programmed during configuration or can be adjusted dynamically using the PHASESEL, PHASEDIR, PHASESTEP, and PHASELOADREG ports.

The LOCK signal is asserted when the PLL determines it has achieved lock and de-asserted if a loss of lock is detected.

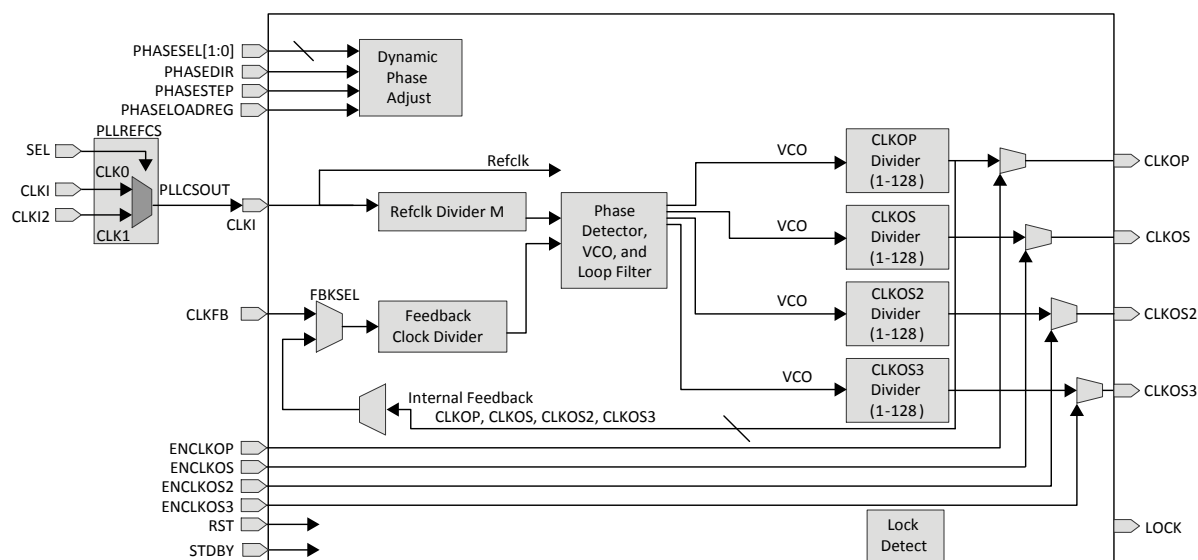


Figure 2.5. General Purpose PLL Diagram

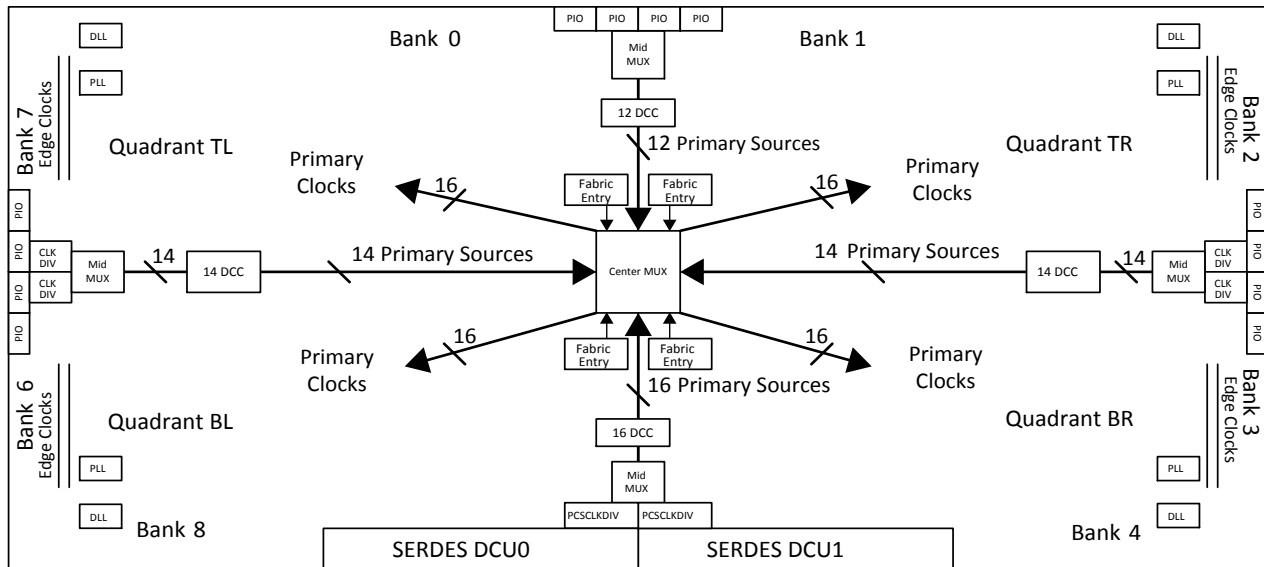


Figure 2.6. LFE5UM/LFE5UM5G-85 Clocking

2.5.1. Primary Clocks

The ECP5/ECP5-5G device family provides low-skew, high fan-out clock distribution to all synchronous elements in the FPGA fabric through the Primary Clock Network.

The primary clock network is divided into four clocking quadrants: Top Left (TL), Bottom Left (BL), Top Right (TR), and Bottom Right (BR). Each of these quadrants has 16 clocks that can be distributed to the fabric in the quadrant.

The Lattice Diamond software can automatically route each clock to one of the four quadrants up to a maximum of 16 clocks per quadrant. The user can change how the clocks are routed by specifying a preference in the Lattice Diamond software to locate the clock to specific. The ECP5/ECP5-5G device provides the user with a maximum of 64 unique clock input sources that can be routed to the primary Clock network.

Primary clock sources are:

- Dedicated clock input pins
- PLL outputs
- CLKDIV outputs
- Internal FPGA fabric entries (with minimum general routing)
- SERDES/PCS/PCSDIV clocks
- OSC clock

These sources are routed to one of four clock switches called a Mid Mux. The outputs of the Mid MUX are routed to the center of the FPGA where another clock switch, called the Center MUX, is used to route the primary clock sources to primary clock distribution to the ECP5/ECP5-5G fabric. These routing muxes are shown in [Figure 2.6](#). Since there is a maximum of 60 unique clock input sources to the clocking quadrants, there are potentially 64 unique clock domains that can be used in the ECP5/ECP5-5G Device. For more information about the primary clock tree and connections, refer to [ECP5 and ECP5-5G sysClock PLL/DLL Design and Usage Guide \(TN1263\)](#).

2.5.1.1. Dynamic Clock Control

The Dynamic Clock Control (DCC), Quadrant Clock enable/disable feature allows internal logic control of the quadrant primary clock network. When a clock network is disabled, the clock signal is static and not toggle. All the logic fed by that clock will not toggle, reducing the overall power consumption of the device. The disable function will not create glitch and increase the clock latency to the primary clock network.

This DCC controls the clock sources from the Primary CLOCK MIDMUX before they are fed to the Primary Center MUXs that drive the quadrant clock network. For more information about the DCC, refer to [ECP5 and ECP5-5G sysClock PLL/DLL Design and Usage Guide \(TN1263\)](#).

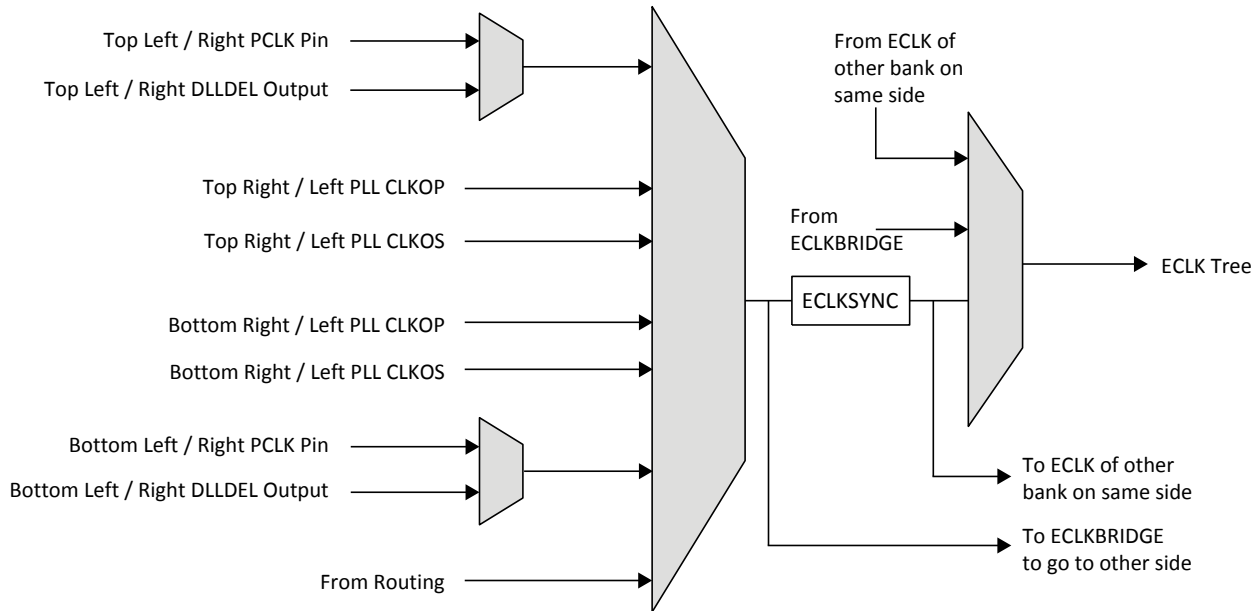


Figure 2.8. Edge Clock Sources per Bank

The edge clocks have low injection delay and low skew. They are used for DDR Memory or Generic DDR interfaces. For detailed information on Edge Clock connections, refer to [ECP5 and ECP5-5G sysClock PLL/DLL Design and Usage Guide \(TN1263\)](#).

2.6. Clock Dividers

ECP5/ECP5-5G devices have two clock dividers, one on the left side and one on the right side of the device. These are intended to generate a slower-speed system clock from a high-speed edge clock. The block operates in a $\div 2$, $\div 3.5$ mode and maintains a known phase relationship between the divided down clock and the high-speed clock based on the release of its reset signal.

The clock dividers can be fed from selected PLL outputs, external primary clock pins multiplexed with the DDRDEL Slave Delay or from routing. The clock divider outputs serve as primary clock sources and feed into the clock distribution network. The Reset (RST) control signal resets input and asynchronously forces all outputs to low. The SLIP signal slips the outputs one cycle relative to the input clock. For further information on clock dividers, refer to [ECP5 and ECP5-5G sysClock PLL/DLL Design and Usage Guide \(TN1263\)](#). Figure 2.9 shows the clock divider connections.

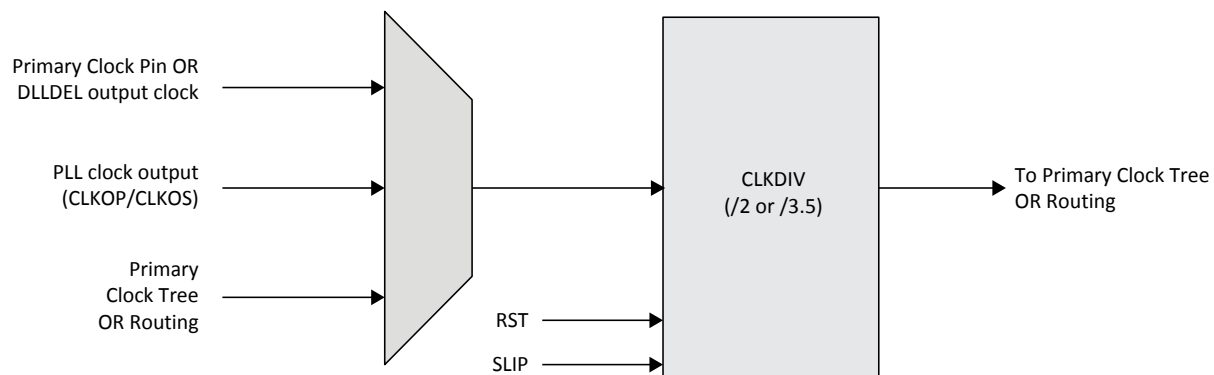


Figure 2.9. ECP5/ECP5-5G Clock Divider Sources

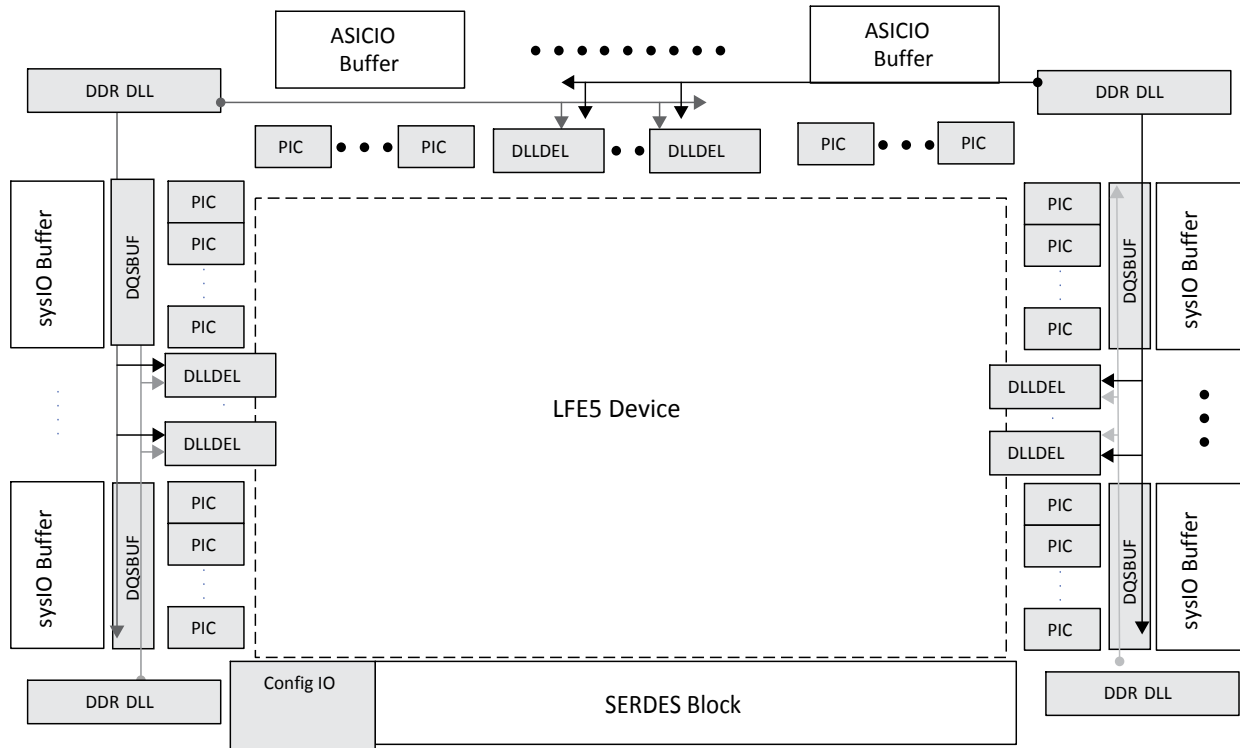


Figure 2.11. ECP5/ECP5-5G DLL Top Level View (For LFE-45 and LFE-85)

2.8. sysMEM Memory

ECP5/ECP5-5G devices contain a number of sysMEM Embedded Block RAM (EBR). The EBR consists of an 18 Kb RAM with memory core, dedicated input registers and output registers with separate clock and clock enable. Each EBR includes functionality to support true dual-port, pseudo dual-port, single-port RAM, ROM and FIFO buffers (via external PFUs).

2.8.1. sysMEM Memory Block

The sysMEM block can implement single port, dual port or pseudo dual port memories. Each block can be used in a variety of depths and widths as listed in Table 2.6 on page 25. FIFOs can be implemented in sysMEM EBR blocks by implementing support logic with PFUs. The EBR block facilitates parity checking by supporting an optional parity bit for each data byte. EBR blocks provide byte-enable support for configurations with 18-bit and 36-bit data widths. For more information, refer to [ECP5 and ECP5-5G Memory Usage Guide \(TN1264\)](#).

2.14. sysI/O Buffer

Each I/O is associated with a flexible buffer referred to as a sysI/O buffer. These buffers are arranged around the periphery of the device in groups referred to as banks. The sysI/O buffers allow users to implement the wide variety of standards that are found in today's systems including LVDS, HSUL, BLVDS, SSTL Class I and II, LVCMOS, LVTTTL, LVPECL, and MIPI.

2.14.1. sysI/O Buffer Banks

ECP5/ECP5-5G devices have seven sysI/O buffer banks, two banks per side at Top, Left and Right, plus one at the bottom left side. The bottom left side bank (Bank 8) is a shared I/O bank. The I/Os in that bank contains both dedicated and shared I/O for sysConfig function. When a shared pin is not used for configuration, it is available as a user I/O. For LFE5-85 devices, there is an additional I/O bank (Bank 4) that is not available in other device in the family.

In ECP5/ECP5-5G devices, the Left and Right sides are tailored to support high performance interfaces, such as DDR2, DDR3, LPDDR2, LPDDR3 and other high speed source synchronous standards. The banks on the Left and Right sides of the devices feature LVDS input and output buffers, data-width gearing, and DQSBUF block to support DDR2/3 and LPDDR2/3 interfaces. The I/Os on the top and bottom banks do not have LVDS input and output buffer, and gearing logic, but can use LVCMOS to emulate most of differential output signaling.

Each sysIO bank has its own I/O supply voltage (V_{CCIO}). In addition, the banks on the Left and Right sides of the device, have voltage reference input (shared I/O pin), V_{REF1} per bank, which allow it to be completely independent of each other. The V_{REF} voltage is used to set the threshold for the referenced input buffers, such as SSTL. Figure 2.25 shows the seven banks and their associated supplies.

In ECP5/ECP5-5G devices, single-ended output buffers and ratioed input buffers (LVTTTL, and LVCMOS) are powered using V_{CCIO} . LVTTTL, LVCMOS33, LVCMOS25 and LVCMOS12 can also be set as fixed threshold inputs independent of V_{CCIO} .

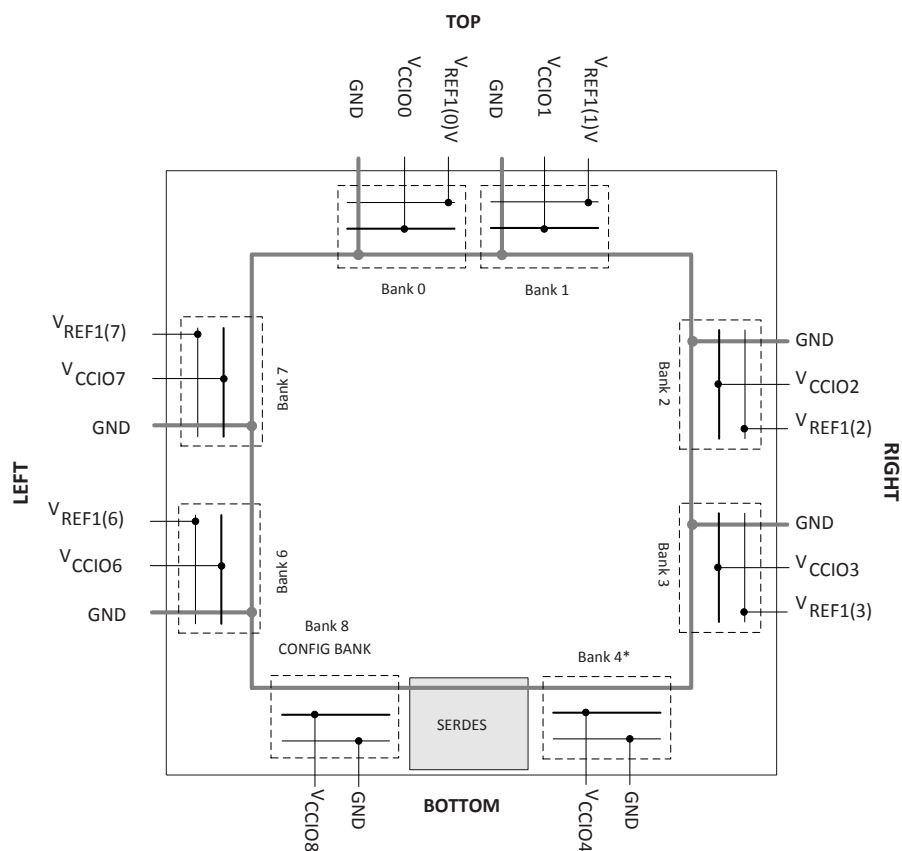


Figure 2.25. ECP5/ECP5-5G Device Family Banks

3.14.6. LVPECL33

The ECP5/ECP5-5G devices support the differential LVPECL standard. This standard is emulated using complementary LVCMOS outputs in conjunction with a parallel resistor across the driver outputs. The LVPECL input standard is supported by the LVDS differential input buffer. The scheme shown in Figure 3.3 is one possible solution for point-to-point signals.

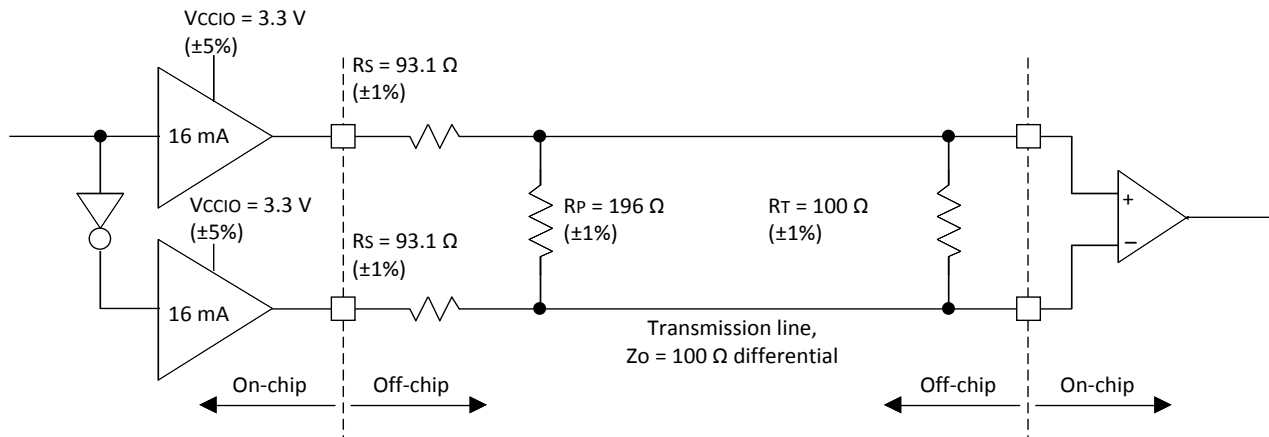


Figure 3.3. Differential LVPECL33

Over recommended operating conditions.

Table 3.16. LVPECL33 DC Conditions

Parameter	Description	Typical	Unit
V _{CCIO}	Output Driver Supply (±5%)	3.30	V
Z _{OUT}	Driver Impedance	10	Ω
R _S	Driver Series Resistor (±1%)	93	Ω
R _P	Driver Parallel Resistor (±1%)	196	Ω
R _T	Receiver Termination (±1%)	100	Ω
V _{OH}	Output High Voltage	2.05	V
V _{OL}	Output Low Voltage	1.25	V
V _{OD}	Output Differential Voltage	0.80	V
V _{CM}	Output Common Mode Voltage	1.65	V
Z _{BACK}	Back Impedance	100.5	Ω
I _{DC}	DC Output Current	12.11	mA

Note: For input buffer, see LVDS Table 3.13 on page 55.

Table 3.20. Register-to-Register Performance

Function	–8 Timing	Unit
Basic Functions		
16-Bit Decoder	441	MHz
32-Bit Decoder	441	MHz
64-Bit Decoder	332	MHz
4:1 Mux	441	MHz
8:1 Mux	441	MHz
16:1 Mux	441	MHz
32:1 Mux	441	MHz
8-Bit Adder	441	MHz
16-Bit Adder	441	MHz
64-Bit Adder	441	MHz
16-Bit Counter	384	MHz
32-Bit Counter	317	MHz
64-Bit Counter	263	MHz
64-Bit Accumulator	288	MHz
Embedded Memory Functions		
1024x18 True-Dual Port RAM (Write Through or Normal), with EBR Output Registers	272	MHz
1024x18 True-Dual Port RAM (Read-Before-Write), with EBR Output Registers	214	MHz
Distributed Memory Functions		
16 x 2 Pseudo-Dual Port or 16 x 4 Single Port RAM (One PFU)	441	MHz
16 x 4 Pseudo-Dual Port (Two PFUs)	441	MHz
DSP Functions		
9 x 9 Multiplier (All Registers)	225	MHz
18 x 18 Multiplier (All Registers)	225	MHz
36 x 36 Multiplier (All Registers)	225	MHz
18 x 18 Multiply-Add/Sub (All Registers)	225	MHz
18 x 18 Multiply/Accumulate (Input and Output Registers)	225	MHz

Notes:

1. These functions were generated using Lattice Diamond design software tool. Exact performance may vary with the device and the design software tool version. The design software tool uses internal parameters that have been characterized but are not tested on every device.
2. Commercial timing numbers are shown. Industrial numbers are typically slower and can be extracted from Lattice Diamond design software tool.

3.16. Derating Timing Tables

Logic timing provided in the following sections of this data sheet and the Diamond design tools are worst case numbers in the operating range. Actual delays at nominal temperature and voltage for best case process, can be much better than the values given in the tables. The Diamond design tool can provide logic timing numbers at a particular temperature and voltage.

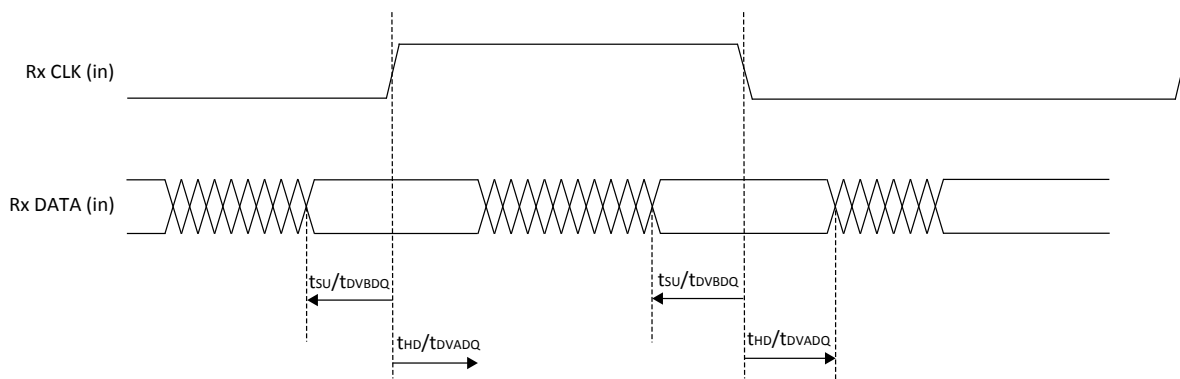


Figure 3.6. Receiver RX.CLK.Centered Waveforms

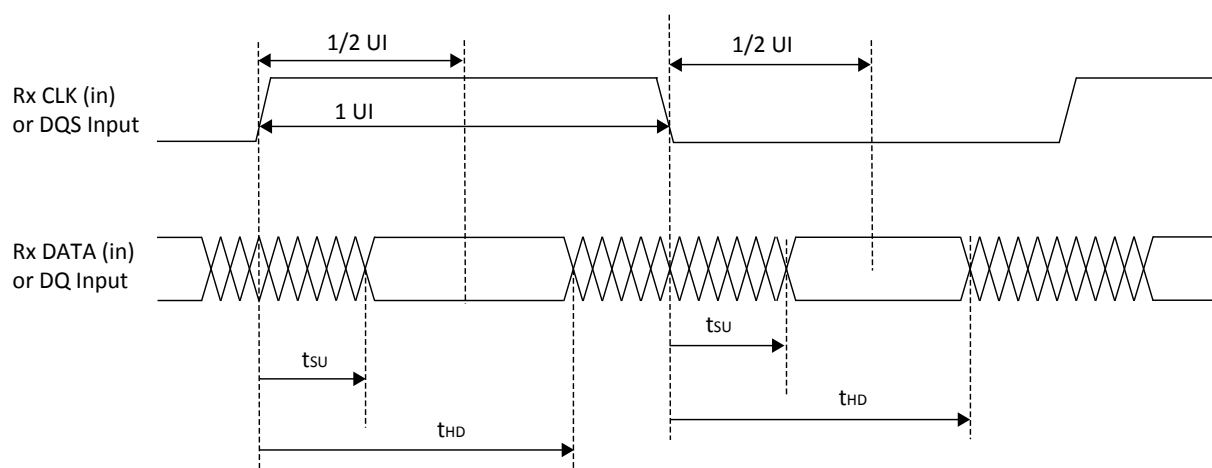


Figure 3.7. Receiver RX.CLK.Aligned and DDR Memory Input Waveforms

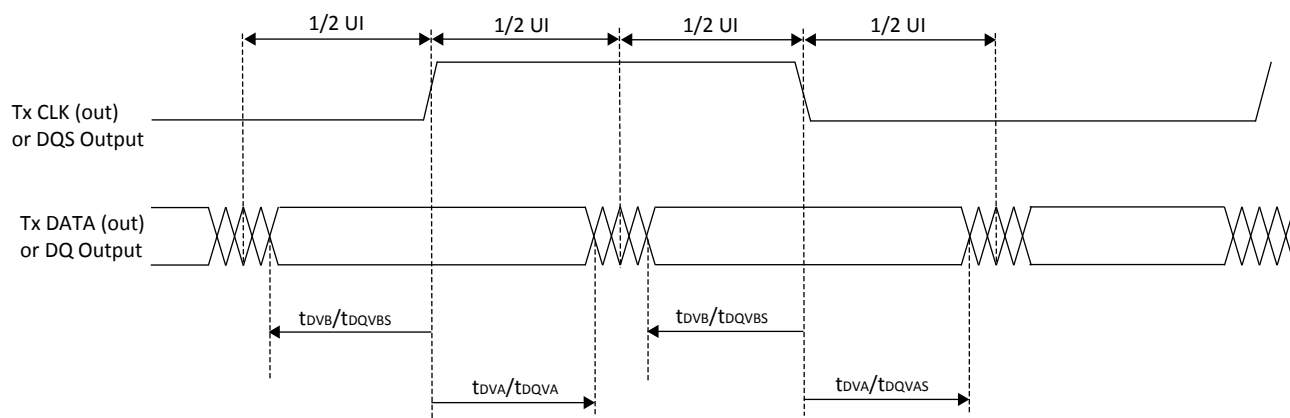


Figure 3.8. Transmit TX.CLK.Centered and DDR Memory Output Waveforms

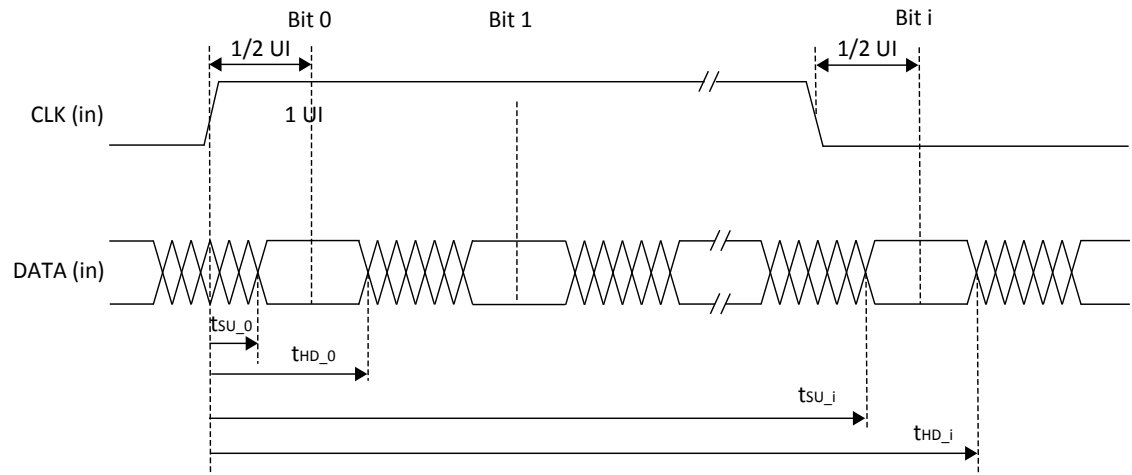


Figure 3.11. Receiver DDRX71_RX Waveforms

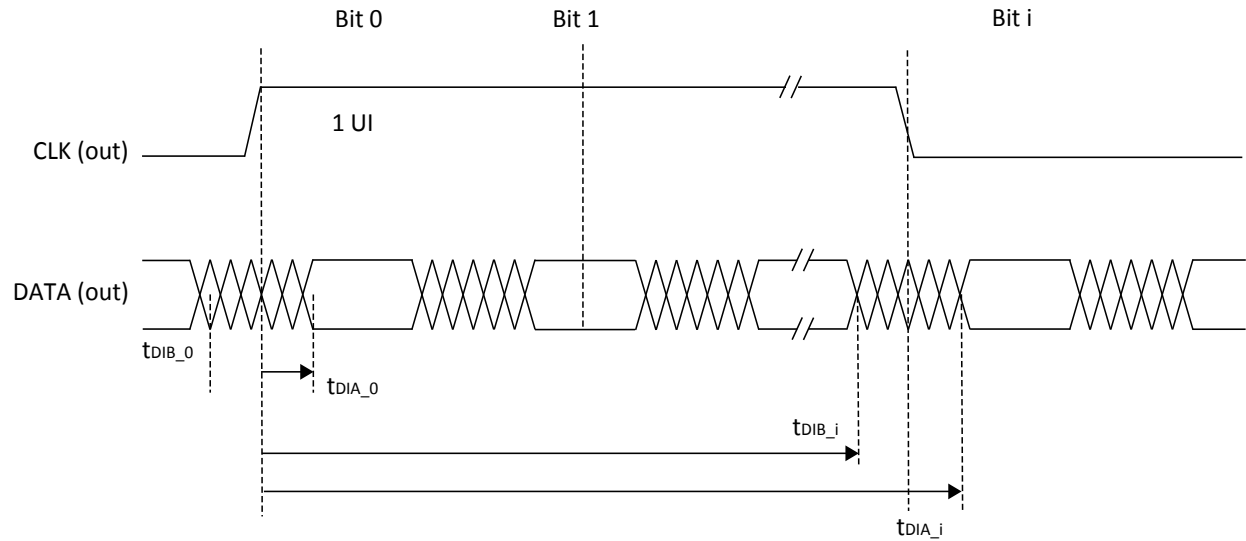


Figure 3.12. Transmitter DDRX71_TX Waveforms

3.20. SERDES High-Speed Data Transmitter

Table 3.24. Serial Output Timing and Levels

Symbol	Description	Min	Typ	Max	Unit
V _{TX-DIFF-PP}	Peak-Peak Differential voltage on selected amplitude ^{1, 2}	-25%	—	25%	mV, p-p
V _{TX-CM-DC}	Output common mode voltage	—	V _{CCHTX} / 2	—	mV, p-p
T _{TX-R}	Rise time (20% to 80%)	50	—	—	ps
T _{TX-F}	Fall time (80% to 20%)	50	—	—	ps
T _{TX-CM-AC-P}	RMS AC peak common-mode output voltage	—	—	20	mV
Z _{TX_SE}	Single ended output impedance for 50/75 Ω	-20%	50/75	20%	Ω
	Single ended output impedance for 6K Ω	-25%	6K	25%	Ω
RL _{TX_DIFF}	Differential return loss (with package included) ³	—	—	-10	dB
RL _{TX_COM}	Common mode return loss (with package included) ³	—	—	-6	dB

Notes:

1. Measured with 50 Ω Tx Driver impedance at V_{CCHTX}±5%.
2. Refer to [ECP5 and ECP5-5G SERDES/PCS Usage Guide \(TN1261\)](#) for settings of Tx amplitude.
3. Return los = -10 dB (differential), -6 dB (common mode) for 100 MHz ≤ f ≤ 1.6 GHz with 50 Ω output impedance configuration. This includes degradation due to package effects.

Table 3.25. Channel Output Jitter

Description	Frequency	Min	Typ	Max	Unit
Deterministic	5 Gb/s	—	—	TBD	UI, p-p
Random	5 Gb/s	—	—	TBD	UI, p-p
Total	5 Gb/s	—	—	TBD	UI, p-p
Deterministic	3.125 Gb/s	—	—	0.17	UI, p-p
Random	3.125 Gb/s	—	—	0.25	UI, p-p
Total	3.125 Gb/s	—	—	0.35	UI, p-p
Deterministic	2.5 Gb/s	—	—	0.17	UI, p-p
Random	2.5 Gb/s	—	—	0.20	UI, p-p
Total	2.5 Gb/s	—	—	0.35	UI, p-p
Deterministic	1.25 Gb/s	—	—	0.10	UI, p-p
Random	1.25 Gb/s	—	—	0.22	UI, p-p
Total	1.25 Gb/s	—	—	0.24	UI, p-p

Notes:

1. Values are measured with PRBS 2⁷-1, all channels operating, FPGA logic active, I/Os around SERDES pins quiet, reference clock @ 10X mode.
2. For ECP5-5G family devices only.

3.24. SERDES External Reference Clock

The external reference clock selection and its interface are a critical part of system applications for this product. Table 3.29 specifies reference clock requirements, over the full range of operating conditions.

Table 3.29. External Reference Clock Specification (refclkp/refclkn)

Symbol	Description	Min	Typ	Max	Unit
F_{REF}	Frequency range	50	—	320	MHz
$F_{REF-PPM}$	Frequency tolerance ¹	–1000	—	1000	ppm
$V_{REF-IN-SE}$	Input swing, single-ended clock ^{2,4}	200	—	V_{CCAUXA}	mV, p-p
$V_{REF-IN-DIFF}$	Input swing, differential clock	200	—	$2 \cdot V_{CCAUXA}$	mV, p-p differential
V_{REF-IN}	Input levels	0	—	$V_{CCAUXA} + 0.4$	V
D_{REF}	Duty cycle ³	40	—	60	%
T_{REF-R}	Rise time (20% to 80%)	200	500	1000	ps
T_{REF-F}	Fall time (80% to 20%)	200	500	1000	ps
$Z_{REF-IN-TERM-DIFF}$	Differential input termination	–30%	100/HiZ	+30%	Ω
$C_{REF-IN-CAP}$	Input capacitance	—	—	7	pF

Notes:

- Depending on the application, the PLL_LOL_SET and CDR_LOL_SET control registers may be adjusted for other tolerance values as described in [ECP5 and ECP5-5G SERDES/PCS Usage Guide \(TN1261\)](#).
- The signal swing for a single-ended input clock must be as large as the p-p differential swing of a differential input clock to get the same gain at the input receiver. With single-ended clock, a reference voltage needs to be externally connected to CLKREFN pin, and the input voltage needs to be swung around this reference voltage.
- Measured at 50% amplitude.
- Single-ended clocking is achieved by applying a reference voltage V_{REF} on REFCLKN input, with the clock applied to REFCLKP input pin. V_{REF} should be set to mid-point of the REFCLKP voltage swing.

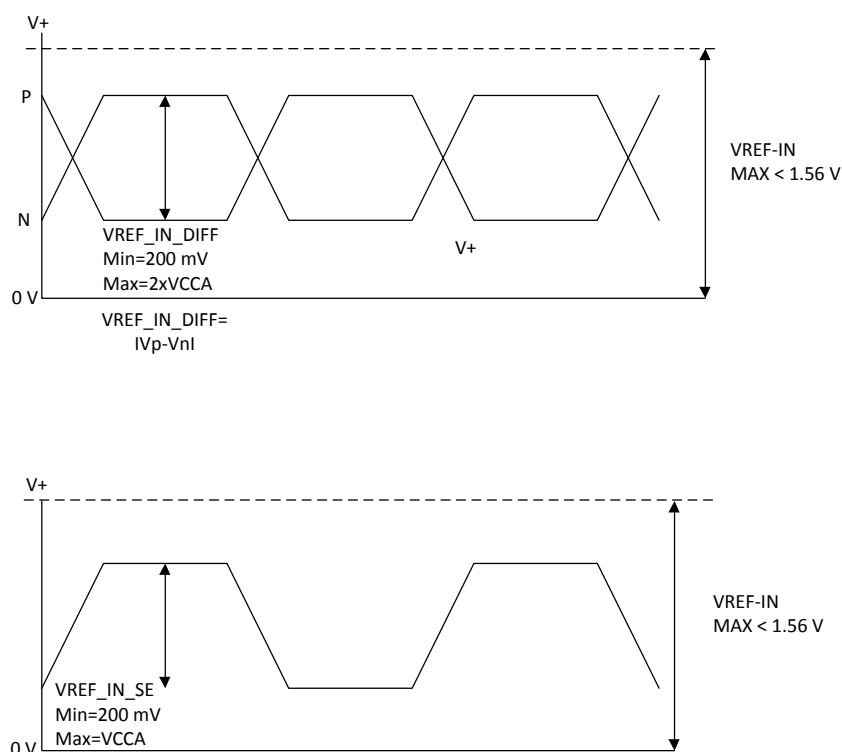


Figure 3.14. SERDES External Reference Clock Waveforms

3.25. PCI Express Electrical and Timing Characteristics

3.25.1. PCIe (2.5 Gb/s) AC and DC Characteristics

Over recommended operating conditions.

Table 3.30. PCIe (2.5 Gb/s)

Symbol	Description	Test Conditions	Min	Typ	Max	Unit
Transmit¹						
UI	Unit interval	—	399.88	400	400.12	ps
V _{TX-DIFF_P-P}	Differential peak-to-peak output	—	0.8	1.0	1.2	V
V _{TX-DE-RATIO}	De-emphasis differential output voltage ratio	—	–3	–3.5	–4	dB
V _{TX-CM-AC_P}	RMS AC peak common-mode output voltage	—	—	—	20	mV
V _{TX-RCV-DETECT}	Amount of voltage change allowed during receiver detection	—	—	—	600	mV
V _{TX-CM-DC}	Tx DC common mode voltage	—	0	—	V _{CCHTX}	V
I _{TX-SHORT}	Output short circuit current	V _{TX-D+} =0.0 V V _{TX-D-} =0.0 V	—	—	90	mA
Z _{TX-DIFF-DC}	Differential output impedance	—	80	100	120	Ω
RL _{TX-DIFF}	Differential return loss	—	10	—	—	dB
RL _{TX-CM}	Common mode return loss	—	6.0	—	—	dB
T _{TX-RISE}	Tx output rise time	20% to 80%	0.125	—	—	UI
T _{TX-FALL}	Tx output fall time	20% to 80%	0.125	—	—	UI
L _{TX-SKEW}	Lane-to-lane static output skew for all lanes in port/link	—	—	—	1.3	ns
T _{TX-EYE}	Transmitter eye width	—	0.75	—	—	UI
T _{TX-EYE-MEDIAN-TO-MAX-JITTER}	Maximum time between jitter median and maximum deviation from median	—	—	—	0.125	UI
Receive^{1,2}						
UI	Unit Interval	—	399.88	400	400.12	ps
V _{RX-DIFF_P-P}	Differential peak-to-peak input voltage	—	0.34 ³	—	1.2	V
V _{RX-IDLE-DET-DIFF_P-P}	Idle detect threshold voltage	—	65	—	340 ³	mV
V _{RX-CM-AC_P}	RMS AC peak common-mode input voltage	—	—	—	150	mV
Z _{RX-DIFF-DC}	DC differential input impedance	—	80	100	120	Ω
Z _{RX-DC}	DC input impedance	—	40	50	60	Ω
Z _{RX-HIGH-IMP-DC}	Power-down DC input impedance	—	200K	—	—	Ω
RL _{RX-DIFF}	Differential return loss	—	10	—	—	dB
RL _{RX-CM}	Common mode return loss	—	6.0	—	—	dB

Notes:

1. Values are measured at 2.5 Gb/s.
2. Measured with external AC-coupling on the receiver.
3. Not in compliance with PCI Express 1.1 standard.

Table 3.36. Receive and Jitter Tolerance

Symbol	Description	Test Conditions	Min	Typ	Max	Unit
RL _{RX_DIFF}	Differential return loss	From 100 MHz to 2.5 GHz	10	—	—	dB
RL _{RX_CM}	Common mode return loss	From 100 MHz to 2.5 GHz	6	—	—	dB
Z _{RX_DIFF}	Differential termination resistance	—	80	100	120	Ω
J _{RX_DJ} ^{2, 3, 4}	Deterministic jitter tolerance (peak-to-peak)	—	—	—	0.37	UI
J _{RX_RJ} ^{2, 3, 4}	Random jitter tolerance (peak-to-peak)	—	—	—	0.18	UI
J _{RX_SJ} ^{2, 3, 4}	Sinusoidal jitter tolerance (peak-to-peak)	—	—	—	0.10	UI
J _{RX_TJ} ^{1, 2, 3, 4}	Total jitter tolerance (peak-to-peak)	—	—	—	0.65	UI
T _{RX_EYE}	Receiver eye opening	—	0.35	—	—	UI

Notes:

1. Total jitter includes deterministic jitter, random jitter and sinusoidal jitter.
2. Jitter values are measured with each high-speed input AC coupled into a 50 Ω impedance.
3. Jitter and skew are specified between differential crossings of the 50% threshold of the reference signal.
4. Jitter tolerance, Differential Input Sensitivity and Receiver Eye Opening parameters are characterized when Full Rx Equalization is enabled.

3.29. Gigabit Ethernet/SGMII(1.25Gbps)/CPRI LV E.12 Electrical and Timing Characteristics

3.29.1. AC and DC Characteristics

Table 3.37. Transmit

Symbol	Description	Test Conditions	Min	Typ	Max	Unit
T _{RF}	Differential rise/fall time	20% to 80%	—	80	—	ps
Z _{TX_DIFF_DC}	Differential impedance	—	80	100	120	Ω
J _{TX_DDJ} ^{2, 3}	Output data deterministic jitter	—	—	—	0.10	UI
J _{TX_TJ} ^{1, 2, 3}	Total output data jitter	—	—	—	0.24	UI

Notes:

1. Total jitter includes both deterministic jitter and random jitter. The random jitter is the total jitter minus the actual deterministic jitter.
2. Jitter values are measured with each CML output AC coupled into a 50 Ω impedance (100 Ω differential impedance).
3. Jitter and skew are specified between differential crossings of the 50% threshold of the reference signal.

Table 3.38. Receive and Jitter Tolerance

Symbol	Description	Test Conditions	Min	Typ	Max	Unit
RL _{RX_DIFF}	Differential return loss	From 100 MHz to 1.25 GHz	10	—	—	dB
RL _{RX_CM}	Common mode return loss	From 100 MHz to 1.25 GHz	6	—	—	dB
Z _{RX_DIFF}	Differential termination resistance	—	80	100	120	Ω
J _{RX_DJ} ^{1, 2, 3, 4}	Deterministic jitter tolerance (peak-to-peak)	—	—	—	0.34	UI
J _{RX_RJ} ^{1, 2, 3, 4}	Random jitter tolerance (peak-to-peak)	—	—	—	0.26	UI
J _{RX_SJ} ^{1, 2, 3, 4}	Sinusoidal jitter tolerance (peak-to-peak)	—	—	—	0.11	UI
J _{RX_TJ} ^{1, 2, 3, 4}	Total jitter tolerance (peak-to-peak)	—	—	—	0.71	UI
T _{RX_EYE}	Receiver eye opening	—	0.29	—	—	UI

Notes:

1. Total jitter includes deterministic jitter, random jitter and sinusoidal jitter.
2. Jitter values are measured with each high-speed input AC coupled into a 50 Ω impedance.
3. Jitter and skew are specified between differential crossings of the 50% threshold of the reference signal.
4. Jitter tolerance, Differential Input Sensitivity and Receiver Eye Opening parameters are characterized when Full Rx Equalization is enabled.

3.30. SMPTE SD/HD-SDI/3G-SDI (Serial Digital Interface) Electrical and Timing Characteristics

3.30.1. AC and DC Characteristics

Table 3.39. Transmit

Symbol	Description	Test Conditions	Min	Typ	Max	Unit
BR _{SDO}	Serial data rate	—	270	—	2975	Mb/s
T _{JALIGNMENT} ²	Serial output jitter, alignment	270 Mb/s ⁶	—	—	0.2	UI
T _{JALIGNMENT} ²	Serial output jitter, alignment	1485 Mb/s	—	—	0.2	UI
T _{JALIGNMENT} ^{1, 2}	Serial output jitter, alignment	2970 Mb/s	—	—	0.3	UI
T _{JTIMING}	Serial output jitter, timing	270 Mb/s ⁶	—	—	0.2	UI
T _{JTIMING}	Serial output jitter, timing	1485 Mb/s	—	—	1	UI
T _{JTIMING}	Serial output jitter, timing	2970 Mb/s	—	—	2	UI

Notes:

1. Timing jitter is measured in accordance with SMPTE serial data transmission standards.
2. Jitter is defined in accordance with SMPTE RP1 184-1996 as: jitter at an equipment output in the absence of input jitter.
3. All Tx jitter are measured at the output of an industry standard cable driver, with the Lattice SERDES device configured to 50 Ω output impedance connecting to the external cable driver with differential signaling.
4. The cable driver drives: RL=75 Ω, AC-coupled at 270, 1485, or 2970 Mb/s.
5. All LFE5UM/LFE5UM5G devices are compliant with all SMPTE compliance tests, except 3G-SDI Level-A pathological compliance pattern test.
6. 270 Mb/s is supported with Rate Divider only.

Table 3.40. Receive

Symbol	Description	Test Conditions	Min	Typ	Max	Unit
BR _{SDI}	Serial input data rate	—	270	—	2970	Mb/s

Table 3.41. Reference Clock

Symbol	Description	Test Conditions	Min	Typ	Max	Unit
F _{VCLK}	Video output clock frequency	—	54	—	148.5	MHz
DC _V	Duty cycle, video clock	—	45	50	55	%

Note: SD-SDI (270 Mb/s) is supported with Rate Divider only. For Single Rate: Reference Clock = 54 MHz and Rate Divider = /2. For Tri-Rate: Reference Clock = 148.5 MHz and Rate Divider = /11.

3.31. sysCONFIG Port Timing Specifications

Over recommended operating conditions.

Table 3.42. ECP5/ECP5-5G sysCONFIG Port Timing Specifications

Symbol	Parameter		Min	Max	Unit
POR, Configuration Initialization, and Wakeup					
t_{ICFG}	Time from the Application of V_{CC} , V_{CCAUX} or V_{CCIO8} (whichever is the last) to the rising edge of INITN	—	—	33	ms
t_{VMC}	Time from t_{ICFG} to the valid Master CCLK	—	—	5	us
t_{CZ}	CCLK from Active to High-Z	—	—	300	ns
Master CCLK					
f_{MCLK}	Frequency	All selected frequencies	–20	20	%
$t_{MCLK-DC}$	Duty Cycle	All selected frequencies	40	60	%
All Configuration Modes					
t_{PRGM}	PROGRAMN LOW pulse accepted	—	110	—	ns
t_{PRGMRJ}	PROGRAMN LOW pulse rejected	—	—	50	ns
t_{INITL}	INITN LOW time	—	—	55	ns
t_{DPPINT}	PROGRAMN LOW to INITN LOW	—	—	70	ns
$t_{DPPDONE}$	PROGRAMN LOW to DONE LOW	—	—	80	ns
t_{IODISS}	PROGRAMN LOW to I/O Disabled	—	—	150	ns
Slave SPI					
f_{CCLK}	CCLK input clock frequency	—	—	60	MHz
t_{CCLKH}	CCLK input clock pulsewidth HIGH	—	6	—	ns
t_{CCLKL}	CCLK input clock pulsewidth LOW	—	6	—	ns
t_{STSU}	CCLK setup time	—	1	—	ns
t_{STH}	CCLK hold time	—	1	—	ns
t_{STCO}	CCLK falling edge to valid output	—	—	10	ns
t_{STOZ}	CCLK falling edge to valid disable	—	—	10	ns
t_{STOV}	CCLK falling edge to valid enable	—	—	10	ns
t_{SCS}	Chip Select HIGH time	—	25	—	ns
t_{SCSS}	Chip Select setup time	—	3	—	ns
t_{SCSH}	Chip Select hold time	—	3	—	ns
Master SPI					
f_{CCLK}	Max selected CCLK output frequency	—	—	62	MHz
t_{CCLKH}	CCLK output clock pulse width HIGH	—	3.5	—	ns
t_{CCLKL}	CCLK output clock pulse width LOW	—	3.5	—	ns
t_{STSU}	CCLK setup time	—	5	—	ns
t_{STH}	CCLK hold time	—	1	—	ns
t_{CSSPI}	INITN HIGH to Chip Select LOW	—	100	200	ns
t_{CFGX}	INITN HIGH to first CCLK edge	—	—	150	ns
Slave Serial					
f_{CCLK}	CCLK input clock frequency	—	—	66	MHz
t_{SSCH}	CCLK input clock pulse width HIGH	—	5	—	ns
t_{SSCL}	CCLK input clock pulse width LOW	—	5	—	ns
t_{SUSCDI}	CCLK setup time	—	0.5	—	ns
$t_{HS CDI}$	CCLK hold time	—	1.5	—	ns

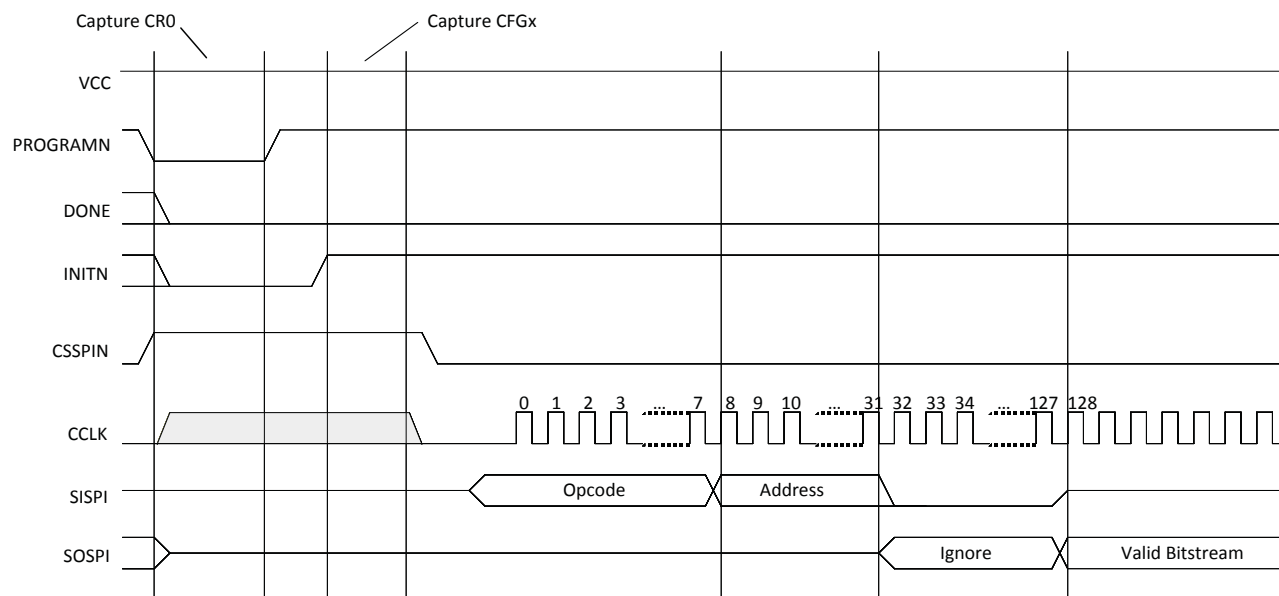


Figure 3.22. Master SPI Configuration Waveforms

3.32. JTAG Port Timing Specifications

Over recommended operating conditions.

Table 3.43. JTAG Port Timing Specifications

Symbol	Parameter	Min	Max	Units
f_{MAX}	TCK clock frequency	—	25	MHz
t_{BTCPH}	TCK [BSCAN] clock pulse width high	20	—	ns
t_{BTCPL}	TCK [BSCAN] clock pulse width low	20	—	ns
t_{BTS}	TCK [BSCAN] setup time	10	—	ns
t_{BTH}	TCK [BSCAN] hold time	8	—	ns
t_{BTRF}	TCK [BSCAN] rise/fall time	50	—	mV/ns
t_{BTCO}	TAP controller falling edge of clock to valid output	—	10	ns
$t_{BTCODIS}$	TAP controller falling edge of clock to valid disable	—	10	ns
t_{BTCOEN}	TAP controller falling edge of clock to valid enable	—	10	ns
t_{BTCRS}	BSCAN test capture register setup time	8	—	ns
t_{BTCRH}	BSCAN test capture register hold time	25	—	ns
t_{BUTCO}	BSCAN test update register, falling edge of clock to valid output	—	25	ns
$t_{BTUODIS}$	BSCAN test update register, falling edge of clock to valid disable	—	25	ns
$t_{BTUPOEN}$	BSCAN test update register, falling edge of clock to valid enable	—	25	ns

4.2. PICs and DDR Data (DQ) Pins Associated with the DDR Strobe (DQS) Pin

PICs Associated with DQS Strobe	PIO within PIC	DDR Strobe (DQS) and Data (DQ) Pins
For Left and Right Edges of the Device Only		
P[L/R] [n-6]	A	DQ
	B	DQ
	C	DQ
	D	DQ
P[L/R] [n-3]	A	DQ
	B	DQ
	C	DQ
	D	DQ
P[L/R] [n]	A	DQS (P)
	B	DQS (N)
	C	DQ
	D	DQ
P[L/R] [n+3]	A	DQ
	B	DQ
	C	DQ
	D	DQ

Note: "n" is a row PIC number.

4.3. Pin Information Summary

4.3.1. LFE5UM/LFE5UM5G

Pin Information Summary		LFE5UM/ LFE5UM5G-25		LFE5UM/LFE5UM5G-45			LFE5UM/LFE5UM5G-85			
Pin Type		285 csfBG	381 caBGA	285 csfBGA	381 caBG	554 caBGA	285 csfBGA	381 caBG	554 caBGA	756 caBGA
General Purpose Inputs/Outputs per Bank	Bank 0	6	24	6	27	32	6	27	32	56
	Bank 1	6	32	6	33	40	6	33	40	48
	Bank 2	21	32	21	32	32	21	34	32	48
	Bank 3	28	32	28	33	48	28	33	48	64
	Bank 4	0	0	0	0	0	0	0	14	24
	Bank 6	26	32	26	33	48	26	33	48	64
	Bank 7	18	32	18	32	32	18	32	32	48
	Bank 8	13	13	13	13	13	13	13	13	13
Total Single-Ended User I/O		118	197	118	203	245	118	205	259	365
VCC		13	20	13	20	24	13	20	24	36
VCCAUX (Core)		3	4	3	4	9	3	4	9	8
VCCIO	Bank 0	1	2	1	2	3	1	2	3	4
	Bank 1	1	2	1	2	3	1	2	3	4
	Bank 2	2	3	2	3	4	2	3	4	4
	Bank 3	2	3	2	3	3	2	3	3	4
	Bank 4	0	0	0	0	0	0	0	2	2
	Bank 6	2	3	2	3	4	2	3	4	4
	Bank 7	2	3	2	3	3	2	3	3	4
	Bank 8	2	2	2	2	2	2	2	2	2